



Supporting Information

for

Direct observation of oxygen-vacancy formation and structural changes in Bi₂WO₆ nanoflakes induced by electron irradiation

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Thickness determination via HRTEM simulation

The thickness of the Bi_2WO_6 nanosheets was determined by HRTEM simulation based on the Bloch-wave method in the Jems software. The crystal structure is from ICSD-67647, the zone axis is [010]. The main simulation parameters were:

illumination model = envelop;

defocus min = 35 nm, step = 1 nm, number = 10;

image dup-x/y = 2, noise% = 2,

start after = 3, number = 18, increment = 3 for iteration parameters

strong parameters = 25, Blochwave parameters: Bethe.

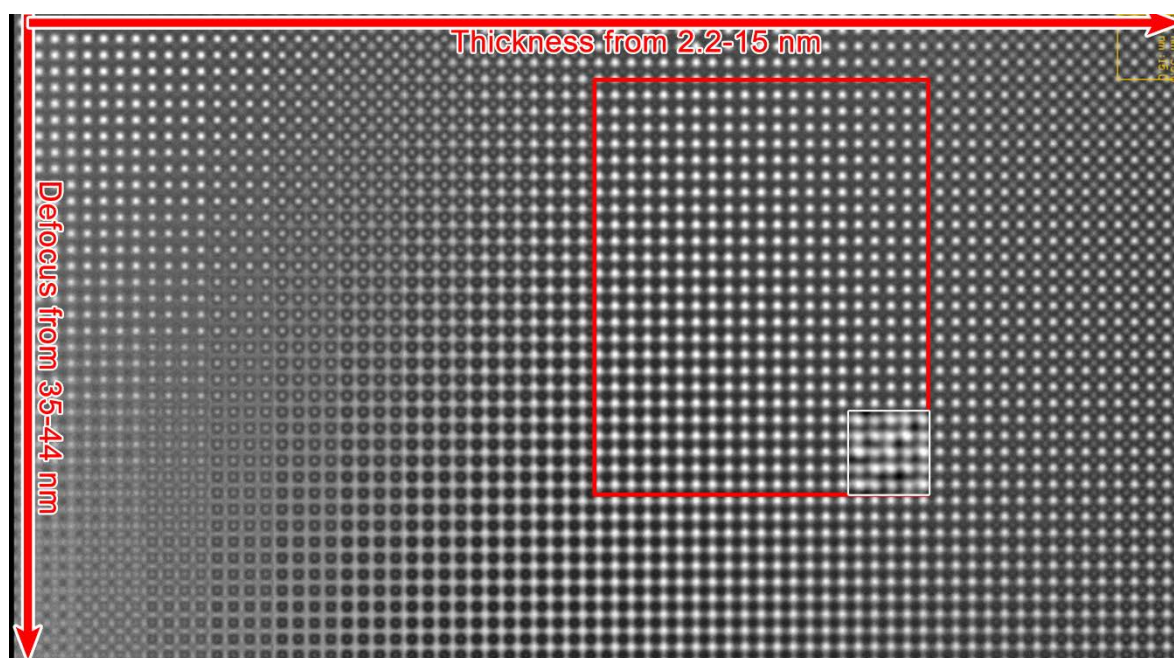


Figure S1: Thickness determination of the Bi_2WO_6 nanosheet by HRTEM image simulation, where the inset is the experimental HRTEM image, and the matched area is marked by a red frame. It indicates the thickness ranges of 6–14 nm.